Ser. No. 10/605,534

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Printed 1/21/2005

In the claims:

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Art Unit: 2816

Please amend claims 1, 11, 17, and 20 as follows:

- 5 1. (currently amended) A voltage sensor circuit comprising:
 - a source-input node having a source-input voltage that is varied by a voltage source, the voltage sensor circuit sensing the source-input voltage of the source-input node;
 - a stable node having a stable voltage that is relatively insensitive to changes in a supply voltage;
- a first current source, responsive to the source-input voltage, for generating a first current that varies with variations in the source-input voltage;
 - a first resistor, coupled to the first current source and receiving the first current, for generating a compare-input voltage on a compare-input node in response to the first current, the compare-input voltage varying with variations in the first current;
 - a second current source for generating a second current that is insensitive to variations in the source-input voltage;
 - a second resistor, coupled to the second current source and receiving the second current, for generating a reference voltage on a reference node in response to the second current, the reference voltage not varying with variations in the second current;
 - a stable node, coupled to the first current source and coupled to the second current source, the stable node having a stable voltage that is relatively insensitive to changes in a supply voltage: and
 - a comparator coupled to the compare-input node and the reference node, for comparing the compare-input voltage to the reference voltage and generating an output voltage at an output node that indicates when the compare-input voltage is above the reference voltage.
- (withdrawn) The voltage sensor circuit of claim 1 wherein the first current source is a substrate-sensing transistor having a substrate node driven by the source-input voltage and a gate driven by a constant bias voltage, the substrate-sensing transistor conducting the first current between the stable node and the compare-input node,

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Ser. No. 10/605,534

Art Unit: 2816

6

Printed 1/21/2005

wherein the first current through the substrate-sensing transistor varies with variations in the source-input voltage,

whereby a substrate-sensing current source generates the first current.

- 5 3. (withdrawn) The voltage sensor circuit of claim 2 wherein the substrate-sensing transistor is a p-channel transistor and the substrate node is an N-well.
 - 4. (withdrawn) The voltage sensor circuit of claim 3 wherein the constant bias voltage is a ground.
 - 5. (withdrawn) The voltage sensor circuit of claim 4 wherein the second current source is a second p-channel transistor having a substrate node connected to the stable node and a gate driven by the constant bias voltage, the second p-channel transistor conducting the second current between the stable node and the reference node.
 - 6. (withdrawn) The voltage sensor circuit of claim 5 wherein a cross-over voltage of the source-input voltage that causes the output voltage to change states varies less than +/- 8% over a temperature range from -40 to +85 degrees C.
 - 7. (original) The voltage sensor circuit of claim 1 wherein the first current source comprises:
 - a first mirror transistor having a channel that conducts the first current between the stable node and the compare-input node in response to a first gate node;
- a first setting transistor, with a gate connected to the first gate node, having a channel that conducts a first setting current between the stable node and the first gate node;
 - a first sensing transistor having a channel that conducts a portion of the first setting current from the first gate node, the first sensing transistor having a gate connected to the source-input voltage;
- 30 wherein the second current source comprises:

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Ser. No. 10/605,534 Art Unit: 2816 7

Printed 1/21/2005

- a second mirror transistor having a channel that conducts the second current between the stable node and the reference node in response to a second gate node;
- a second setting transistor, with a gate connected to the second gate node, having a channel that conducts a second setting current between the stable node and the second gate node; and
- a second sensing transistor having a channel that conducts a portion of the second setting current from the second gate node, the second sensing transistor having a gate connected to a fixed voltage.
- 8. (original) The voltage sensor circuit of claim 7 wherein the fixed voltage applied to the gate of the second sensing transistor is the stable voltage.
 - 9. (original) The voltage sensor circuit of claim 8 wherein the first and second mirror transistors and the first and second setting transistors are p-channel transistors; wherein the first and second sensing transistors are n-channel transistors.
 - 10. (original) The voltage sensor circuit of claim 9 wherein a cross-over voltage of the source-input voltage that causes the output voltage to change states varies less than +/-4% over a temperature range from -40 to +85 degrees C.
 - 11. (currently amended) The voltage sensor circuit of claim 7 further comprising: a voltage generator for generating the stable voltage on the stable node that is independent of a supply voltage of the supply voltage to the comparator.
- 25 12. (original) The voltage sensor circuit of claim 11 wherein the voltage generator is a band-gap voltage generator.
 - 13. (original) The voltage sensor circuit of claim 12 wherein the comparator is powered by the supply voltage.
 - 14. (withdrawn) A substrate-sensing voltage sensor comprising:

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Ser. No. 10/605,534 Art Unit: 2816 8

Printed 1/21/2005

- a voltage generator for generating a stable voltage on a stable node, the stable voltage being relatively insensitive to variations in a supply voltage;
- a comparator that generates an output by comparing voltages of a compare-input node and a reference node;
- a first transistor having a channel connected between the stable node and the compareinput node, with a gate connected to a bias voltage and a substrate connected to a source-input voltage that is varied by a voltage source;
 - a first resistor connected between the compare-input node and a ground;
 - a second transistor having a channel connected between the stable node and the reference
 - node, with a gate connected to the bias voltage; and a second resistor connected between the reference node and the ground, whereby the source-input voltage from the voltage source is sensed by substrate-sensing of the first transistor.
- 15 (withdrawn) The substrate-sensing voltage sensor of claim 14 wherein the first transistor is a p-channel transistor with a source connected to the stable node, a drain connected to the compare-input node, and the source-input voltage connected to a n-type substrate or an N-well under the first transistor; wherein the second transistor is a p-channel transistor with a source connected to the

stable node, a drain connected to the reference node, and the stable voltage connected to a n-type substrate or an N-well under the second transistor.

- 16. (withdrawn) The substrate-sensing voltage sensor of claim 15 wherein the bias voltage is the ground,
- 25 whereby the first and second transistors have grounded gates.
 - 17. (currently amended) A temperature-insensitive voltage sensor comprising: an input voltage from a varying voltage source;
- compare means, having a first input and a second input, for comparing voltages on the first and second inputs to generate an output;

Ser. No. 10/605,534 Art Unit: 2816

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9

Printed 1/21/2005

- first resistor means, receiving a first current, for generating a compare voltage on the first input of the compare means;
- first mirror transistor means, having a gate connected to a first gate node, for generating the first current from a stable node to the first input of the compare means and to the first resistor means;
- first current-source transistor means, having a gate and a drain connected to the first gate node and a source connected to the stable node, for generating a first gate voltage on the first gate node;
- first sensing transistor means, having a gate driven by the input voltage, for varying a first sink current from the first gate node in response to the input voltage;
- second resistor means, receiving a second current, for generating a reference voltage on the second input of the compare means;
- second mirror transistor means, having a gate connected to a second gate node, for generating the second current from the stable node to the second input of the compare means and to the second resistor means;
- second current-source transistor means, having a gate and a drain connected to the second gate node and a source connected to the stable node, for generating a second gate voltage on the second gate node; and
- second sensing transistor means, having a gate driven by a constant voltage, for generating a second sink current from the second gate node.
- whereby variations in the first current due to temperature variations are compensated by variations in the second current that are due to the temperature variations.
- 18. (original) The temperature-insensitive voltage sensor of claim 17 further comprising: stable-voltage generator means for generating a stable voltage on the stable node, the 25 stable voltage being insensitive to a supply voltage to the compare means.
 - 19. (original) The temperature-insensitive voltage sensor of claim 18 wherein the first and second sensing transistor means are n-channel transistors having grounded sources;

Ser. No. 10/605,534

Art Unit: 2816

10

Printed 1/21/2005

wherein the first and second mirror transistor means are p-channel transistors having sources connected to the stable node;

wherein the first and second current-source transistor means are p-channel transistors having sources connected to the stable node and each having a drain shorted to a gate.

The temperature-insensitive voltage sensor of claim 19 20. (currently amended) wherein the constant voltage to the gate of the second sensing transistor means is a the is the stable voltage.

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